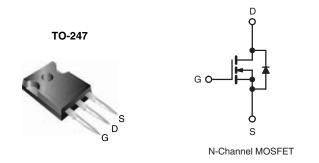


Vishay Siliconix

Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	500			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.23		
Q _g (Max.) (nC)	120			
Q _{gs} (nC)	32			
Q _{gd} (nC)	52			
Configuration	Single			



FEATURES

• Low Gate Charge Qq Results in Simple Drive Requirement



 Improved Gate, Avalanche and Dynamic dV/dt RoHS Ruggedness

- Characterized Capacitance and Avalanche Voltage and Current
- Lead (Pb)-free Available

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Full Bridge Converters
- Power Factor Correction Boost

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRP22N50APbF
	SiHFP22N50A-E3
SnPb	IRP22N50A
	SiHFP22N50A

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherw PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	500		
Gate-Source Voltage			V _{GS}	± 30	V	
Ocation on Paris Oceans		T _C = 25 °C	_	22	А	
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	14		
Pulsed Drain Current ^a			I _{DM}	88		
Linear Derating Factor				2.2	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	1180	mJ	
Repetitive Avalanche Current ^a			I _{AR}	22	Α	
Repetitive Avalanche Energy ^a			E _{AR}	28	mJ	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	277	W	
Peak Diode Recovery dV/dtc			dV/dt	4.8	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6.00.0*1	0.00 140		10	lbf ⋅ in	
	6-32 or M3 screw			1.1	N · m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Starting T_J = 25 °C, L = 4.87 mH, R_G = 25 $\Omega,\,I_{AS}$ = 22 A (see fig. 12).
- c. $I_{SD} \leq 22$ A, $dI/dt \leq 190$ A/µs, $V_{DD} \leq V_{DS}, \, T_{J} \leq 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP22N50A, SiHFP22N50A

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THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	40		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.45		

PARAMETER	SYMBOL	TES*	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.55	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	V _{DS} = V _{GS} , I _D = 250 μA		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 30 V		-	-	± 100	nA
Zava Cata Valtaga Dvain Current	1	V _{DS} = 500 V, V _{GS} = 0 V		-	-	25	μΑ
Zero Gate Voltage Drain Current	I _{DSS} V _{DS} = 400 V, V _{GS} = 0 V, T _J = 125 °C		V _{GS} = 0 V, T _J = 125 °C	-	-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 13 A ^b	-	-	0.23	Ω
Forward Transconductance	9 fs	V _{DS} = 50 V, I _D = 13 A ^b		12	-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		3450	-	-
Output Capacitance	C _{oss}	,			513	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	27	-	
Outrut Constitue			V _{DS} = 1.0 V, f = 1.0 MHz		4935		- pF -
Output Capacitance	C_{oss}	$V_{GS} = 0 V$	V _{GS} = 0 V V _{DS} = 400 V, f = 1.0 MHz		137		
Effective Output Capacitance	C _{oss} eff.]	V _{DS} = 0 V to 400 V ^c		264		
Total Gate Charge	Qg			-	-	120	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 22 \text{ A}, V_{DS} = 400 \text{ V},$ see fig. 6 and 13 ^b	-	-	32	
Gate-Drain Charge	Q _{gd}]	goo ngi o ana 10	-	-	52	
Turn-On Delay Time	t _{d(on)}	V_{DD} = 250 V, I_D = 22 A, R_G = 4.3 Ω , R_D = 11 Ω , see fig. 10 ^b		-	26	-	- ns
Rise Time	t _r			-	94	-	
Turn-Off Delay Time	t _{d(off)}			-	47	-	
Fall Time	t _f			-	47	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	22	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	88	A
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 22A, V _{GS} = 0 V ^b		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 22 A, dI/dt = 100 A/μs ^b		-	570	850	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	6.1	9.2	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	on is dor	ninated b	v L _s and	[D]	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS} .



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

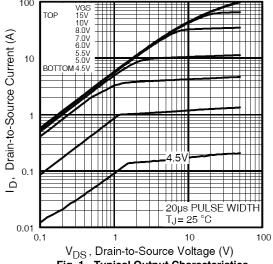


Fig. 1 - Typical Output Characteristics

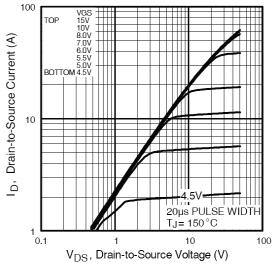
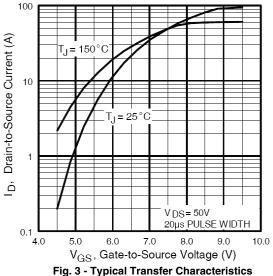


Fig. 2 - Typical Output Characteristics



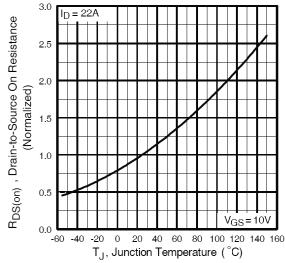


Fig. 4 - Normalized On-Resistance vs. Temperature

IRFP22N50A, SiHFP22N50A

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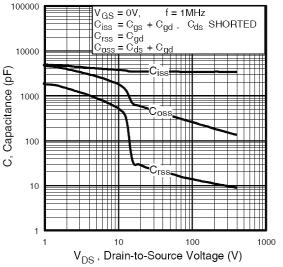


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

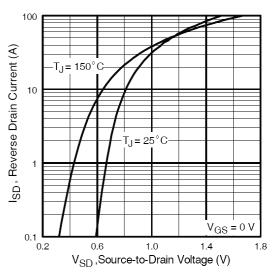


Fig. 7 - Typical Source-Drain Diode Forward Voltage

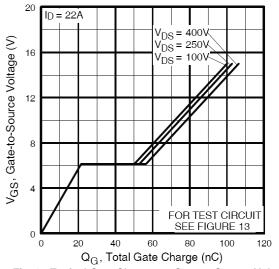


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

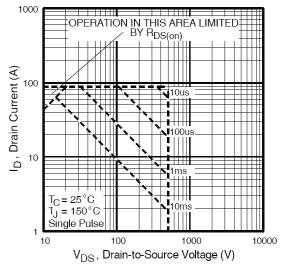
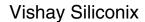


Fig. 8 - Maximum Safe Operating Area





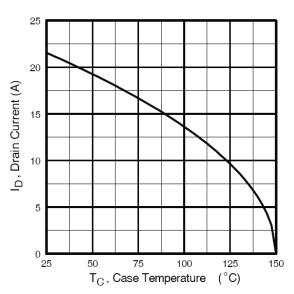


Fig. 9 - Maximum Drain Current vs. Case Temperature

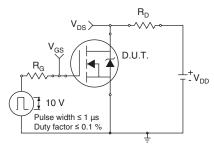


Fig. 10a - Switching Time Test Circuit

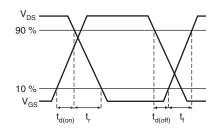


Fig. 10b - Switching Time Waveforms

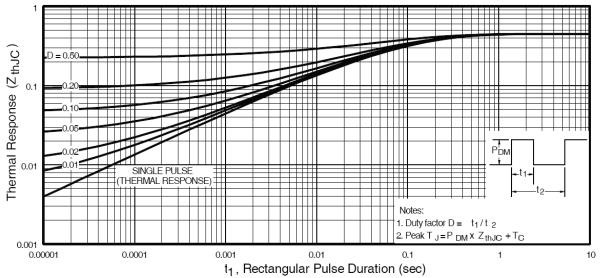


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

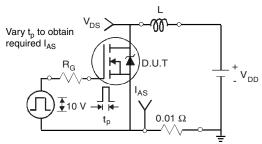


Fig. 12a - Unclamped Inductive Test Circuit

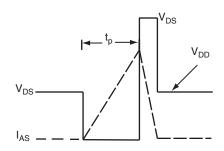


Fig. 12b - Unclamped Inductive Waveforms

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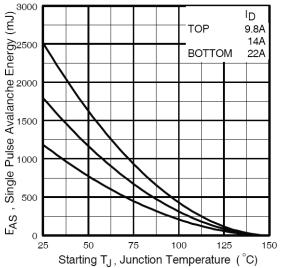


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

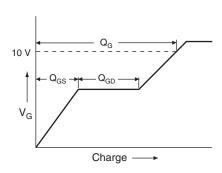


Fig. 13a - Basic Gate Charge Waveform

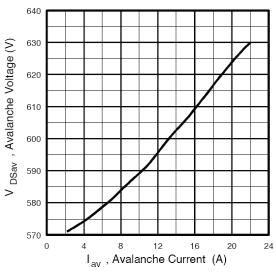


Fig. 12d - Typical Drain-to-Source Voltage vs. **Avalanche Current**

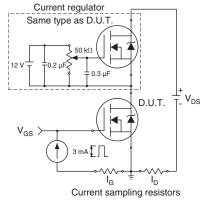
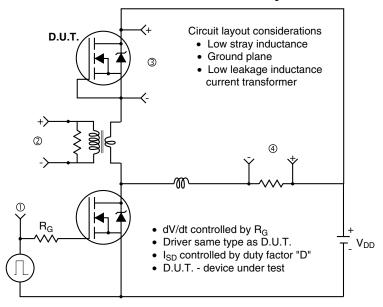
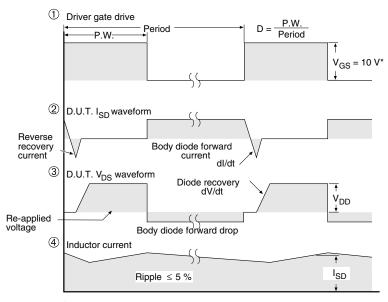


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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